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(Accelerated life testing  
 (Type II  
 (Monte Carlo Markov Chain)  
 (sampler  
 (lcm21)  
 censored data)  
 Gibss )

### Abstract

This paper deals with accelerated life testing. Bayesian approach for accelerated life test, will be developed taking into consideration three parameters Weibull distribution representing failure times, and Arrhenius life-stress model (with existence of thermal stress factor of different levels). We assumed that the data representing the failure times are mixed data including complete and censored data of the second type.

Full Bayesian analysis has been carried out by using one way of the simulation of Markov chain Monte Carlo which is the Gibbs sampler, finally the data used in the analysis represent the failure time of the conductors type lcm21 from Ninevah electric management office.

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Extrapolation

(Environment use)

.(Accelerated environment)

-1

(items)

(Very large scale integrated VLSI)

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(Mean time to failure MTTF)

(Accelerated life testing)

(Closed form)

1986 (Tierney and Kadane)

)

(Mont Carlo Markov

Mattos ,N.M.C.&

(MCMC)

(

-Chain( MCMC))

2001

Higen,H.S.M.

Arrhenius Relationship or (life-stress model) -  
 Arrhenius Life-stress model -2  
 Arrhenius Life-stress model ( )  
 ( )

Arrhenius Reaction Rate

.1887 Svandle-Arrhenius -  
 (Ebeling, E. 1997) ):

$$R(T) = Ae^{-EA/K.T} \quad \text{..(1)}$$

(Energy : EA. : A. : R  
 ctivation)  
 (8.61738510<sup>-5</sup> (Boltzman's constant) : K  
 e<sup>V/K</sup>(Kelvin)  
 .(Kelvin) : T

: -  
 $L(V) = Ce^{B/V} \quad \text{..(2)}$   
 :  
 ... : L  
 ) : V  
 .(C>0) : C .(  
 : B  
 B ( )

(Nelson, W., 1971, 1990)

(Thomas and Gorton 1963)

-3

(Life time)

(Versatile)

(Shape parameter)

):

Ebeling, E. 1997)

$$f(t; P, \lambda, \gamma) = \frac{P}{\lambda} \left( \frac{t - \gamma}{\lambda} \right)^{P-1} e^{-\left( \frac{t - \gamma}{\lambda} \right)^P} \quad \dots (3)$$

$$t \geq \gamma; P, \lambda > 0; \gamma \geq 0$$

Shape parameter

= P Scale parameter

= λ

Location parameter

= γ

T

(Accelerated life time)

(3)

P

γ, λ

V

n<sub>i</sub>

T<sub>ij</sub>

$$f(t_{ij} | \lambda, P, \gamma) = \frac{P}{\lambda_i} \left( \frac{t_{ij} - \gamma_i}{\lambda_i} \right)^{P-1} e^{-\left( \frac{t_{ij} - \gamma_i}{\lambda_i} \right)^P} \quad \dots(4)$$

$$i = 1, 2, \dots, k; \quad j = 1, 2, \dots, n_i \quad t_{ij} > 0$$

$V_i$

$\lambda_i$

$P$

$\gamma_i$

$V$

$k$

$$\lambda_i = \exp(-(Z_i + \beta_0 + \beta_1 X_i)) \quad \dots(5)$$

$X_i, Z_i$

(Nelson, 1990 )

$\gamma_i$

$$\gamma_i = \alpha * e^{BV_i} \quad \dots(6)$$

$\alpha, B$

(Man, R., N.el al., 1974 )

$\gamma_i$

) (Type II censoring)

(2005 ).

$r_i$

$V_i$

$n_i$

(2005 )  $\beta_0, \beta_1, \alpha, B$  and  $P$

$$L(\beta_0, \beta_1, \alpha, B, P, data) \propto P^r \left( \prod_{i=1}^K \prod_{j=1}^{n_i} (t_{ij} - \alpha e^{BV_i})^{P-1} \right) * \exp(-Pa_0 - PB_0 r - PB_1 a_1 - e^{-PB_0} \sum_{i=1}^K A_i(P, \alpha, B) - PZ_i - PB_1 X_i) \quad \dots(7)$$

$$a_1 = \sum_{i=1}^K r_i X_i; A_i(P, \alpha, B) = \sum_{j=1}^{K_i} (t_{ij} - \alpha e^{BV_i})^{P-1} + (n_i - r_i)(t_i r_i - \alpha e^{BV_i})^P$$

$$a_0 = \sum_{j=1}^K r_i Z_i \quad r = \sum_{i=1}^K r_i$$

:  $\beta_0, \beta_1, \alpha, B, P$

1-3

(4), (5), (6)

$-\infty < \beta_0, \beta_1 < \infty$

$\beta_0, \beta_1$

.....

$$\beta_0, \beta_1 \sim N(0, \tau_i^2) \quad i = 0, 1$$

$$:$$

$$\alpha \sim \exp(c) \quad B \sim \exp(d)$$

$$\Gamma(b, a)$$

$$P$$

Mattos, N.M.C. & Mign ).

(, H.S., 2001

(2007 )  $\beta_0, \beta_1, \alpha, B, P$

$$\pi_1(\beta_0, \beta_1, \alpha, B, P | data) \propto \pi_0(\beta_0) \pi_0(\beta_1) \pi_0(\alpha) \pi_0(B) \pi_0(P) L(\beta_0, \beta_1, \alpha, B, P)$$

$$\pi_1(\beta_0, \beta_1, \alpha, B, P | data) \propto P^{r+a+1} \left( \prod_{i=1}^K \prod_{j=1}^{r_i} (t_{ij} - \alpha e^{B V_i})^{P-1} * \right.$$

$$\left. \exp(-P a_o - P \beta_o r - P \beta_1 a_1 - e^{-P B_o} \sum_{i=1}^K A_i(P, \alpha, B) e^{-P Z_i - P \beta_i X_i} \right.$$

$$\left. - \frac{\beta_0^2}{2\tau_1^2} - \frac{\beta_1^2}{2\tau_2^2} - e\alpha - dB - bP \right) \quad ..(8)$$

$\beta_0, \beta_1, \alpha, B, P$

$P, B, \alpha, \beta_1, \beta_0$

(8)

(Mattos, N.M.C. & Mign, H.S., 2001 ):

$$\pi_1(\beta_0 | \beta_1, \alpha, B, P, data) \propto \exp\left(-PB_0 r - \frac{\beta_0^2}{2\tau_1^2}\right) * \exp\left[-e^{-P\beta_0} \sum_{i=1}^K A_i(\alpha, B, P)e^{-PZ_i - P\beta_1 X_i}\right] \dots(9)$$

$$\pi_1(\beta_1 | \beta_0, \alpha, B, P, data) \propto \exp\left(-PB_1 a_1 - \frac{\beta_1^2}{2\tau_2^2}\right) * \exp\left[-e^{-P\beta_0} \sum_{i=1}^K A_i(\alpha, B, P)e^{-PZ_i - P\beta_1 X_i}\right] \dots(10)$$

$$\pi_1(\alpha | \beta_0, \beta_1, B, P, data) \propto \exp\left(\prod_{i=1}^K \prod_{j=1}^{r_i} (t_{ij} - \alpha e^{BV_i})^{P-1}\right) * \exp\left[-e^{-P\beta_0} \sum_{i=1}^K A_i(\alpha, B, P)e^{-PZ_i - P\beta_1 X_i} - e\alpha\right] \dots(11)$$

$$\pi_1(B | \beta_0, \beta_1, \alpha, P, data) \propto \left(\prod_{i=1}^K \prod_{j=1}^{r_i} (t_{ij} - \alpha e^{BV_i})^{P-1}\right) * \exp\left[-e^{-P\beta_0} \sum_{i=1}^K A_i(\alpha, B, P)e^{-PZ_i - P\beta_1 X_i} - dB\right] \dots(12)$$

$$\pi_1(P | \beta_0, \beta_1, \alpha, B, data) \propto P^{r+a-1} \left(\prod_{i=1}^K \prod_{j=1}^{r_i} (t_{ij} - \alpha e^{BV_i})^{P-1}\right) * \exp\left[-e^{-P\beta_0} \sum_{i=1}^K A_i(\alpha, B, P)e^{-PZ_i - P\beta_1 X_i} - bP\right] \dots(13)$$

(Parametric family)

Parameter estimation

2-3

(5), (5), (4)

).(Gibbs sampling)

(MCMC)

.(2005,

(Win-BUGS)

(Functional form)

(Win-BUGs)

(Log-Con-cave distributions)

(Gilks, W.R and Wild, P. 1992 ) .



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(7)

(Uni -dimensional)

(Complete conditional densities)

$$\frac{\partial^2 \log}{\partial \beta_0^2} \pi_1(\beta_0 | \beta_1, \alpha, B, P),$$

$$\frac{\partial^2 \log}{\partial \beta_1^2} \pi_1(\beta_1 | \beta_0, \alpha, B, P),$$

$$\frac{\partial^2 \log}{\partial \alpha^2} \pi_1(\alpha | \beta_0, \beta_1, B, P),$$

$$\frac{\partial^2 \log}{\partial B^2} \pi_1(B | \beta_0, \beta_1, \alpha, P),$$

$$\frac{\partial^2 \log}{\partial P^2} \pi_1(P | \beta_0, \beta_1, B, \alpha)$$

(12), (11), (10), (9),

– (13)

– 4

(Severity)

(MCMC)

The Arrhenius model

1-4

$\lambda_i$  (4) –

$$\lambda_i = \exp(-(Z_i + \beta_0 + \beta_1 X_i)) \quad \text{..(5)}$$

(2)  $\beta_1 = \beta, \beta_0 = -\beta_0, Z_i = 0, X_i = -1 \forall i$

-lcm21

$V_0 = 5A$

60A, 50A, 30A, 20A, 10A

$r_i$

$n_i$

$V_i$

(Censored)

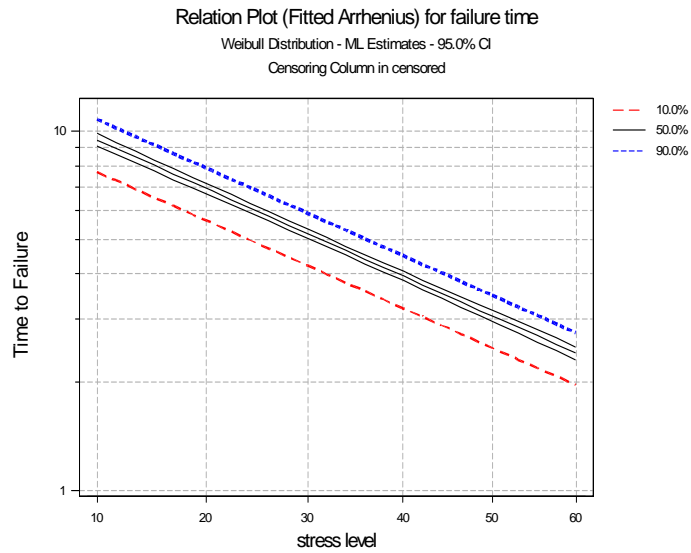
$(n_i - r_i)$

$V_i$   
P

$\lambda_i$

(1) (Minitab 13)

(2005, )



( ) :(1)

$\beta_0, \beta_1, \alpha, B, P$

Win-BUGS

( (BUGS)

(MCMC)

(Mattos, N.M.C. and Mign, H.S 2001 ).

) Doodles

BUGS

BUGS

(

(13), (12), (11), (10), (9)

$\beta_0, \beta_1, \alpha, B, P$

BUGS

Win-BUGS

(Specify a new sampling distribution)



[59]

2012(22)

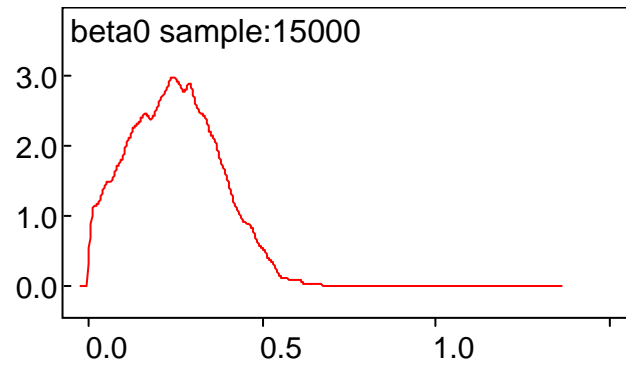
(MC error)

5%

$(\sigma/N^{1/2})$

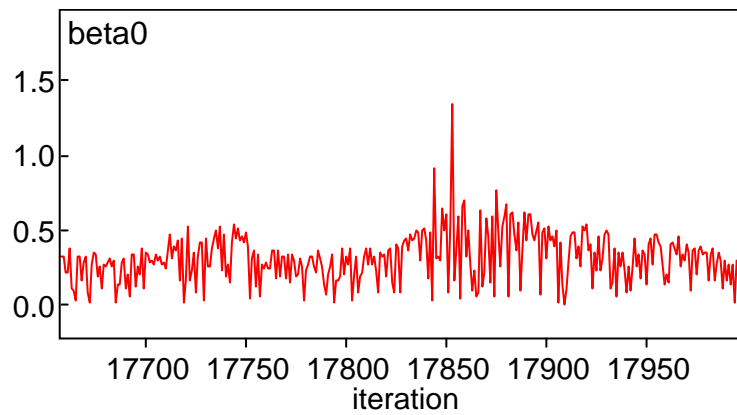
0.00439

$\beta_0$



$\beta_0$

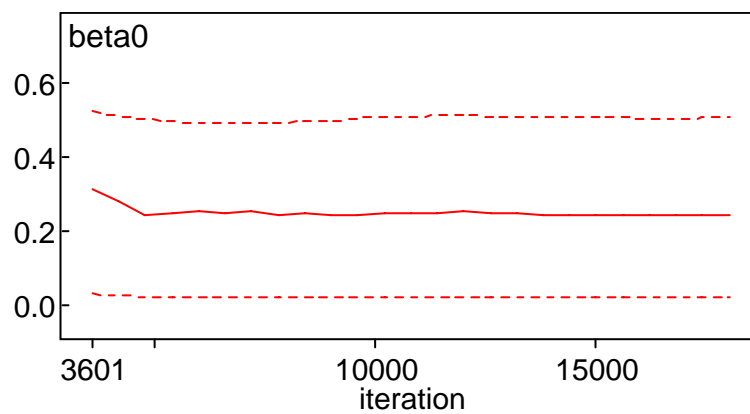
(2)



$\beta_0$

(trace)

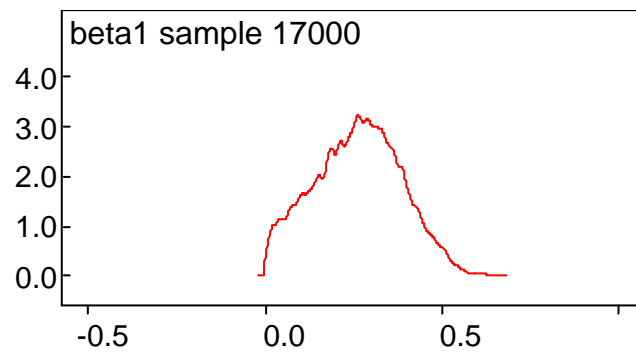
(3)



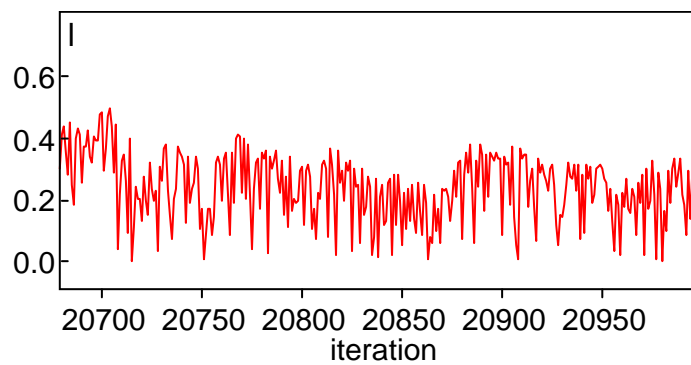
$\beta_0$  (HPD) (4)

node	mean	Sd	MC error	2.5%	median	97.5%	start	sample
Beta 0	0.2518	0.1221	0.004394	0.02417	0.2551	0.4773	501	16500

$-\beta_1$   
 $:\beta_1$  (5) -1  
 $:\beta_1$  (6) -2



$\beta_1$  (5)



$\beta_1$  (trace) (6)

$\alpha$

$\gamma_i$

:

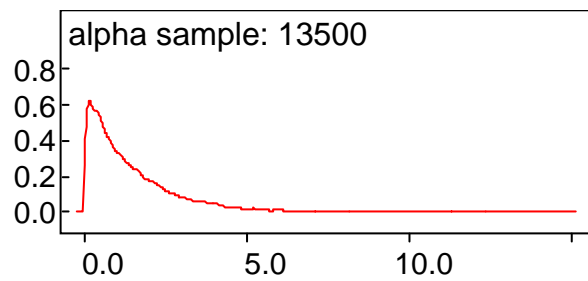
$\alpha$  (7) -1

$\alpha$  (8) -2

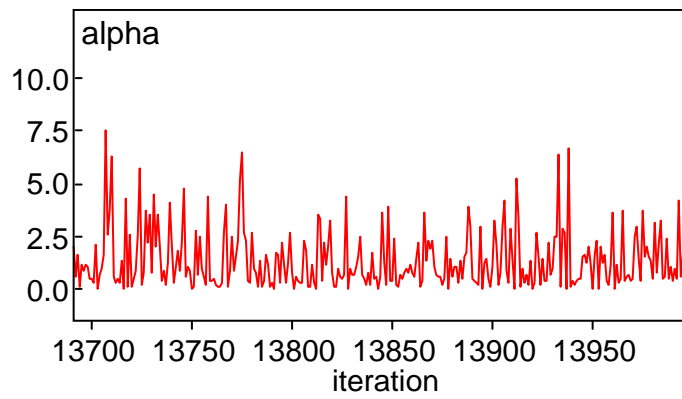
$\alpha$  (9) -3

5% -4

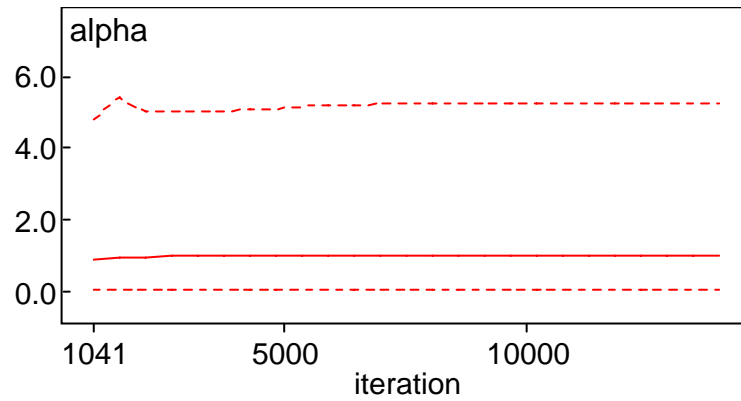
$\alpha$



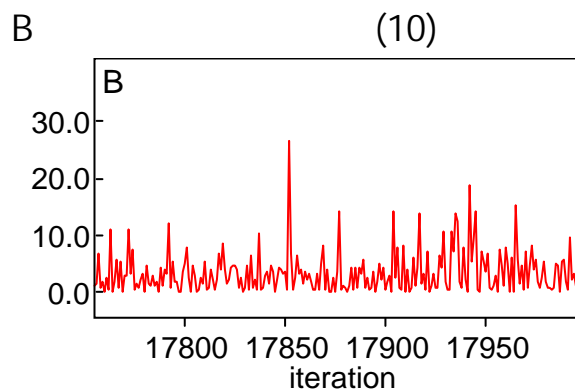
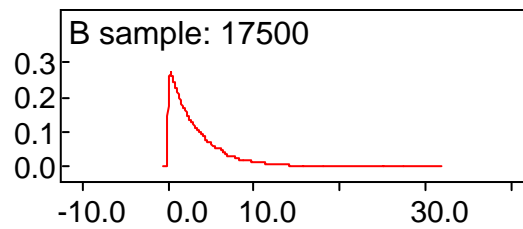
$\alpha$  (7)



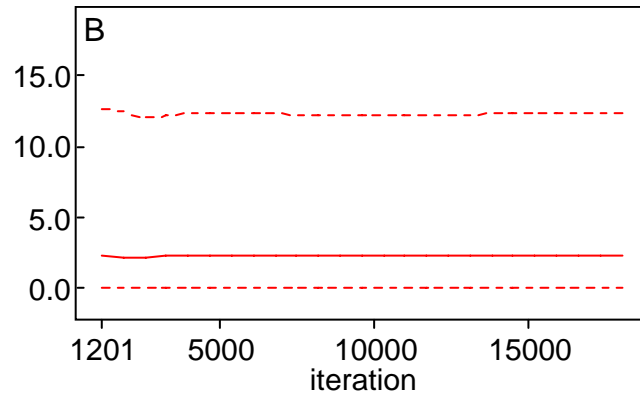
$\alpha$  (trace) (8)



$\alpha$  (HPD) (9)  
 $\gamma_i$  B  
 :  
 B (10) -1  
 B (11) -2  
 B 95% (12) -3



B (trace) (11)



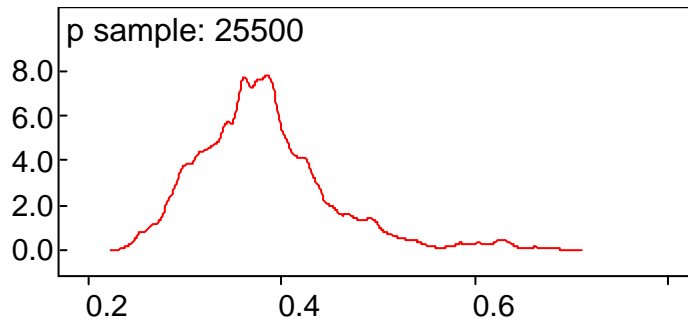
B (HPD) (12)  
P

P (13) -1

P (14) -2

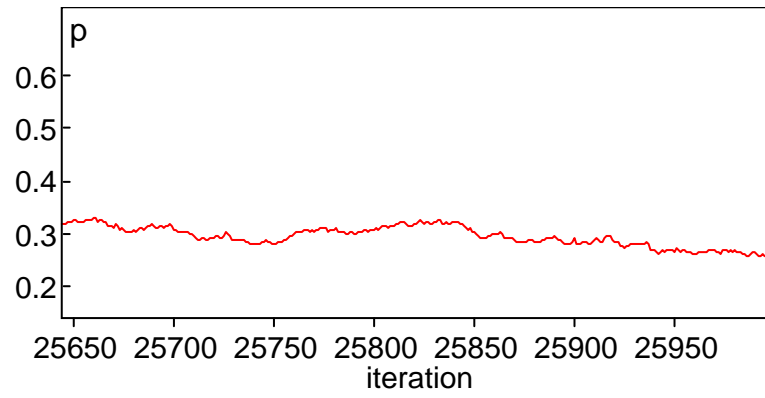
.P 95% (15) -3

5% P -4

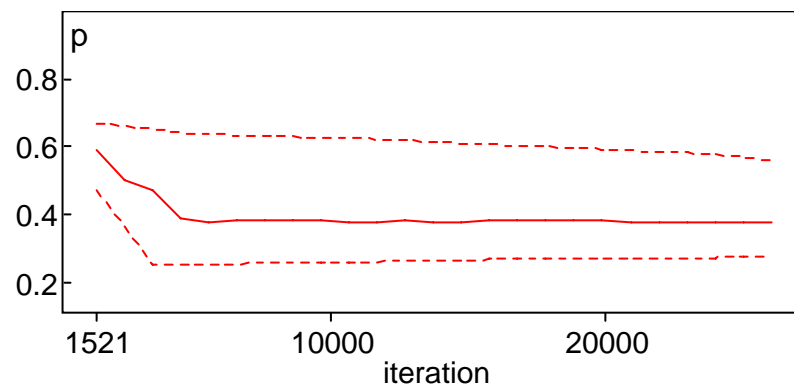


P (13)





P (trace) (14)



P (HPD) (15)

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Win-BUGS -2

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